With the easy-to-use CT technology of the ZEISS METROTOM 1, anyone can efficiently perform complex measurement and inspection tasks with just one scan. Measure and inspect hidden defects and internal structures that cannot be detected with tactile or optical measuring systems.

**ZEISS METROTOM 1**

Inspect the invisible in just one step
The new level of simplicity

zeiss.com/metrotom1
One machine, several advantages

Easy handling
Installation is quick and only little training is needed for safe handling of ZEISS METROTOM 1

Precise measurements
Perform nominal/actual comparisons, dimensional checks, and wall thickness analyses with confidence

Small footprint
With dimensions of 1750 (W) x 1820 (H) x 870 (D) mm, the CT system fits into any metrology lab

Fast return on invest
Acquisition costs as well as cost of ownership are minimal with the low-maintenance system

Applications
Whether medium or small sized parts, plastic or light metal – with ZEISS METROTOM 1, you can inspect a variety of components such as connectors, plastic caps, aluminum parts and more.

Specifications

<table>
<thead>
<tr>
<th>Specification</th>
<th>Value</th>
</tr>
</thead>
<tbody>
<tr>
<td>X-ray source</td>
<td>160 kV</td>
</tr>
<tr>
<td>X-ray detector (pixel)</td>
<td>2.5 k (2,500 x 2,500)</td>
</tr>
<tr>
<td>Measuring volume</td>
<td>165 x 140 mm</td>
</tr>
<tr>
<td>Metrology specification (MPE SD)</td>
<td>5 μm + L/100</td>
</tr>
<tr>
<td>Dimensions (W x H x D)</td>
<td>1,750 x 1,820 x 8,70 mm</td>
</tr>
<tr>
<td>Weight</td>
<td>2,100 kg</td>
</tr>
<tr>
<td>Software (included)</td>
<td>GOM Volume Inspect</td>
</tr>
</tbody>
</table>

High Resolution option
The HR option increases the resolution from 65.3 μm auf 32.6 μm. This allows you to better detect defects and ensure the functionality and quality of your parts.

- You can see even more details and avoid undetected defects
- Improved image quality
- Easy to switch between standard and high resolution mode
- HR option can be quickly and easily installed by the user